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Details

Product Status	Active
Number of LABs/CLBs	1330
Number of Logic Elements/Cells	21280
Total RAM Bits	774144
Number of I/O	150
Number of Gates	-
Voltage - Supply	1.16V ~ 1.24V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	324-LBGA
Supplier Device Package	324-FBGA (19x19)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep4cgx22cf19i7n



Cyclone IV E industrial devices I7 are offered with extended operating temperature range.

Absolute Maximum Ratings

Absolute maximum ratings define the maximum operating conditions for Cyclone IV devices. The values are based on experiments conducted with the device and theoretical modeling of breakdown and damage mechanisms. The functional operation of the device is not implied at these conditions. Table 1–1 lists the absolute maximum ratings for Cyclone IV devices.



Conditions beyond those listed in Table 1–1 cause permanent damage to the device. Additionally, device operation at the absolute maximum ratings for extended periods of time have adverse effects on the device.

Table 1–1. Absolute Maximum Ratings for Cyclone IV Devices ⁽¹⁾

Symbol	Parameter	Min	Max	Unit
V_{CCINT}	Core voltage, PCI Express® (PCIe®) hard IP block, and transceiver physical coding sublayer (PCS) power supply	–0.5	1.8	V
V_{CCA}	Phase-locked loop (PLL) analog power supply	–0.5	3.75	V
V_{CCD_PLL}	PLL digital power supply	–0.5	1.8	V
V_{CCIO}	I/O banks power supply	–0.5	3.75	V
V_{CC_CLKIN}	Differential clock input pins power supply	–0.5	4.5	V
V_{CCH_GXB}	Transceiver output buffer power supply	–0.5	3.75	V
V_{CCA_GXB}	Transceiver physical medium attachment (PMA) and auxiliary power supply	–0.5	3.75	V
V_{CCL_GXB}	Transceiver PMA and auxiliary power supply	–0.5	1.8	V
V_I	DC input voltage	–0.5	4.2	V
I_{OUT}	DC output current, per pin	–25	40	mA
T_{STG}	Storage temperature	–65	150	°C
T_J	Operating junction temperature	–40	125	°C

Note to Table 1–1:

(1) Supply voltage specifications apply to voltage readings taken at the device pins with respect to ground, not at the power supply.

Maximum Allowed Overshoot or Undershoot Voltage

During transitions, input signals may overshoot to the voltage shown in Table 1–2 and undershoot to –2.0 V for a magnitude of currents less than 100 mA and for periods shorter than 20 ns. Table 1–2 lists the maximum allowed input overshoot voltage and the duration of the overshoot voltage as a percentage over the lifetime of the device. The maximum allowed overshoot duration is specified as a percentage of high-time over the lifetime of the device.

Recommended Operating Conditions

This section lists the functional operation limits for AC and DC parameters for Cyclone IV devices. Table 1–3 and Table 1–4 list the steady-state voltage and current values expected from Cyclone IV E and Cyclone IV GX devices. All supplies must be strictly monotonic without plateaus.

Table 1–3. Recommended Operating Conditions for Cyclone IV E Devices ⁽¹⁾, ⁽²⁾ (Part 1 of 2)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$V_{CCINT}^{(3)}$	Supply voltage for internal logic, 1.2-V operation	—	1.15	1.2	1.25	V
	Supply voltage for internal logic, 1.0-V operation	—	0.97	1.0	1.03	V
$V_{CCIO}^{(3), (4)}$	Supply voltage for output buffers, 3.3-V operation	—	3.135	3.3	3.465	V
	Supply voltage for output buffers, 3.0-V operation	—	2.85	3	3.15	V
	Supply voltage for output buffers, 2.5-V operation	—	2.375	2.5	2.625	V
	Supply voltage for output buffers, 1.8-V operation	—	1.71	1.8	1.89	V
	Supply voltage for output buffers, 1.5-V operation	—	1.425	1.5	1.575	V
	Supply voltage for output buffers, 1.2-V operation	—	1.14	1.2	1.26	V
$V_{CCA}^{(3)}$	Supply (analog) voltage for PLL regulator	—	2.375	2.5	2.625	V
$V_{CCD_PLL}^{(3)}$	Supply (digital) voltage for PLL, 1.2-V operation	—	1.15	1.2	1.25	V
	Supply (digital) voltage for PLL, 1.0-V operation	—	0.97	1.0	1.03	V
V_I	Input voltage	—	–0.5	—	3.6	V
V_O	Output voltage	—	0	—	V_{CCIO}	V
T_J	Operating junction temperature	For commercial use	0	—	85	°C
		For industrial use	–40	—	100	°C
		For extended temperature	–40	—	125	°C
		For automotive use	–40	—	125	°C
t_{RAMP}	Power supply ramp time	Standard power-on reset (POR) ⁽⁵⁾	50 μ s	—	50 ms	—
		Fast POR ⁽⁶⁾	50 μ s	—	3 ms	—

Table 1–7. Bus Hold Parameter for Cyclone IV Devices (Part 2 of 2) ⁽¹⁾

Parameter	Condition	V _{CCIO} (V)												Unit
		1.2		1.5		1.8		2.5		3.0		3.3		
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
Bus hold trip point	—	0.3	0.9	0.375	1.125	0.68	1.07	0.7	1.7	0.8	2	0.8	2	V

Note to Table 1–7:

(1) Bus hold trip points are based on the calculated input voltages from the JEDEC standard.

OCT Specifications

Table 1–8 lists the variation of OCT without calibration across process, temperature, and voltage (PVT).

Table 1–8. Series OCT Without Calibration Specifications for Cyclone IV Devices

Description	V_{CCIO} (V)	Resistance Tolerance		Unit
		Commercial Maximum	Industrial, Extended industrial, and Automotive Maximum	
Series OCT without calibration	3.0	±30	±40	%
	2.5	±30	±40	%
	1.8	±40	±50	%
	1.5	±50	±50	%
	1.2	±50	±50	%

OCT calibration is automatically performed at device power-up for OCT-enabled I/Os.

Table 1–9 lists the OCT calibration accuracy at device power-up.

Table 1–9. Series OCT with Calibration at Device Power-Up Specifications for Cyclone IV Devices

Description	V_{CCIO} (V)	Calibration Accuracy		Unit
		Commercial Maximum	Industrial, Extended industrial, and Automotive Maximum	
Series OCT with calibration at device power-up	3.0	±10	±10	%
	2.5	±10	±10	%
	1.8	±10	±10	%
	1.5	±10	±10	%
	1.2	±10	±10	%

The OCT resistance may vary with the variation of temperature and voltage after calibration at device power-up. Use Table 1-10 and Equation 1-1 to determine the final OCT resistance considering the variations after calibration at device power-up. Table 1-10 lists the change percentage of the OCT resistance with voltage and temperature.

Table 1-10. OCT Variation After Calibration at Device Power-Up for Cyclone IV Devices

Nominal Voltage	dR/dT (%/°C)	dR/dV (%/mV)
3.0	0.262	-0.026
2.5	0.234	-0.039
1.8	0.219	-0.086
1.5	0.199	-0.136
1.2	0.161	-0.288

Equation 1-1. Final OCT Resistance (1), (2), (3), (4), (5), (6)

$$\Delta R_V = (V_2 - V_1) \times 1000 \times dR/dV \text{ — (7)}$$

$$\Delta R_T = (T_2 - T_1) \times dR/dT \text{ — (8)}$$

$$\text{For } \Delta R_x < 0; MF_x = 1 / (|\Delta R_x|/100 + 1) \text{ — (9)}$$

$$\text{For } \Delta R_x > 0; MF_x = \Delta R_x/100 + 1 \text{ — (10)}$$

$$MF = MF_V \times MF_T \text{ — (11)}$$

$$R_{\text{final}} = R_{\text{initial}} \times MF \text{ — (12)}$$

Notes to Equation 1-1:

- (1) T_2 is the final temperature.
- (2) T_1 is the initial temperature.
- (3) MF is multiplication factor.
- (4) R_{final} is final resistance.
- (5) R_{initial} is initial resistance.
- (6) Subscript x refers to both V and T .
- (7) ΔR_V is a variation of resistance with voltage.
- (8) ΔR_T is a variation of resistance with temperature.
- (9) dR/dT is the change percentage of resistance with temperature after calibration at device power-up.
- (10) dR/dV is the change percentage of resistance with voltage after calibration at device power-up.
- (11) V_2 is final voltage.
- (12) V_1 is the initial voltage.

Internal Weak Pull-Up and Weak Pull-Down Resistor

Table 1-12 lists the weak pull-up and pull-down resistor values for Cyclone IV devices.

Table 1-12. Internal Weak Pull-Up and Weak Pull-Down Resistor Values for Cyclone IV Devices ⁽¹⁾

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
R _{PU}	Value of the I/O pin pull-up resistor before and during configuration, as well as user mode if you enable the programmable pull-up resistor option	V _{CCIO} = 3.3 V ± 5% ^{(2), (3)}	7	25	41	kΩ
		V _{CCIO} = 3.0 V ± 5% ^{(2), (3)}	7	28	47	kΩ
		V _{CCIO} = 2.5 V ± 5% ^{(2), (3)}	8	35	61	kΩ
		V _{CCIO} = 1.8 V ± 5% ^{(2), (3)}	10	57	108	kΩ
		V _{CCIO} = 1.5 V ± 5% ^{(2), (3)}	13	82	163	kΩ
		V _{CCIO} = 1.2 V ± 5% ^{(2), (3)}	19	143	351	kΩ
R _{PD}	Value of the I/O pin pull-down resistor before and during configuration	V _{CCIO} = 3.3 V ± 5% ⁽⁴⁾	6	19	30	kΩ
		V _{CCIO} = 3.0 V ± 5% ⁽⁴⁾	6	22	36	kΩ
		V _{CCIO} = 2.5 V ± 5% ⁽⁴⁾	6	25	43	kΩ
		V _{CCIO} = 1.8 V ± 5% ⁽⁴⁾	7	35	71	kΩ
		V _{CCIO} = 1.5 V ± 5% ⁽⁴⁾	8	50	112	kΩ

Notes to Table 1-12:

- (1) All I/O pins have an option to enable weak pull-up except the configuration, test, and JTAG pins. The weak pull-down feature is only available for JTAG TCK.
- (2) Pin pull-up resistance values may be lower if an external source drives the pin higher than V_{CCIO}.
- (3) $R_{PU} = (V_{CCIO} - V_I) / I_{R_{PU}}$
Minimum condition: -40°C; V_{CCIO} = V_{CC} + 5%, V_I = V_{CC} + 5% - 50 mV;
Typical condition: 25°C; V_{CCIO} = V_{CC}, V_I = 0 V;
Maximum condition: 100°C; V_{CCIO} = V_{CC} - 5%, V_I = 0 V; in which V_I refers to the input voltage at the I/O pin.
- (4) $R_{PD} = V_I / I_{R_{PD}}$
Minimum condition: -40°C; V_{CCIO} = V_{CC} + 5%, V_I = 50 mV;
Typical condition: 25°C; V_{CCIO} = V_{CC}, V_I = V_{CC} - 5%;
Maximum condition: 100°C; V_{CCIO} = V_{CC} - 5%, V_I = V_{CC} - 5%; in which V_I refers to the input voltage at the I/O pin.

Hot-Socketing

Table 1-13 lists the hot-socketing specifications for Cyclone IV devices.

Table 1-13. Hot-Socketing Specifications for Cyclone IV Devices

Symbol	Parameter	Maximum
I _{IOPIN(DC)}	DC current per I/O pin	300 μA
I _{IOPIN(AC)}	AC current per I/O pin	8 mA ⁽¹⁾
I _{XCVRTX(DC)}	DC current per transceiver TX pin	100 mA
I _{XCVRRX(DC)}	DC current per transceiver RX pin	50 mA

Note to Table 1-13:

- (1) The I/O ramp rate is 10 ns or more. For ramp rates faster than 10 ns, |I_{IOPIN}| = C dv/dt, in which C is the I/O pin capacitance and dv/dt is the slew rate.



During hot-socketing, the I/O pin capacitance is less than 15 pF and the clock pin capacitance is less than 20 pF.

Table 1–20. Differential I/O Standard Specifications for Cyclone IV Devices ⁽¹⁾ (Part 2 of 2)

I/O Standard	V _{CCIO} (V)			V _{ID} (mV)		V _{ICM} (V) ⁽²⁾			V _{OD} (mV) ⁽³⁾			V _{OS} (V) ⁽³⁾		
	Min	Typ	Max	Min	Max	Min	Condition	Max	Min	Typ	Max	Min	Typ	Max
LVDS (Column I/Os)	2.375	2.5	2.625	100	—	0.05	$D_{MAX} \leq 500 \text{ Mbps}$	1.80	247	—	600	1.125	1.25	1.375
						0.55	$500 \text{ Mbps} \leq D_{MAX} \leq 700 \text{ Mbps}$	1.80						
						1.05	$D_{MAX} > 700 \text{ Mbps}$	1.55						
BLVDS (Row I/Os) ⁽⁴⁾	2.375	2.5	2.625	100	—	—	—	—	—	—	—	—	—	—
BLVDS (Column I/Os) ⁽⁴⁾	2.375	2.5	2.625	100	—	—	—	—	—	—	—	—	—	—
mini-LVDS (Row I/Os) ⁽⁵⁾	2.375	2.5	2.625	—	—	—	—	—	300	—	600	1.0	1.2	1.4
mini-LVDS (Column I/Os) ⁽⁵⁾	2.375	2.5	2.625	—	—	—	—	—	300	—	600	1.0	1.2	1.4
RSDS [®] (Row I/Os) ⁽⁵⁾	2.375	2.5	2.625	—	—	—	—	—	100	200	600	0.5	1.2	1.5
RSDS (Column I/Os) ⁽⁵⁾	2.375	2.5	2.625	—	—	—	—	—	100	200	600	0.5	1.2	1.5
PPDS (Row I/Os) ⁽⁵⁾	2.375	2.5	2.625	—	—	—	—	—	100	200	600	0.5	1.2	1.4
PPDS (Column I/Os) ⁽⁵⁾	2.375	2.5	2.625	—	—	—	—	—	100	200	600	0.5	1.2	1.4

Notes to Table 1–20:

- (1) For an explanation of terms used in Table 1–20, refer to “Glossary” on page 1–37.
- (2) V_{IN} range: $0 \text{ V} \leq V_{IN} \leq 1.85 \text{ V}$.
- (3) R_L range: $90 \leq R_L \leq 110 \Omega$.
- (4) There are no fixed V_{IN}, V_{OD}, and V_{OS} specifications for BLVDS. They depend on the system topology.
- (5) The Mini-LVDS, RSDS, and PPDS standards are only supported at the output pins.
- (6) The LVPECL I/O standard is only supported on dedicated clock input pins. This I/O standard is not supported for output pins.

Power Consumption

Use the following methods to estimate power for a design:

- the Excel-based EPE
- the Quartus® II PowerPlay power analyzer feature

The interactive Excel-based EPE is used prior to designing the device to get a magnitude estimate of the device power. The Quartus II PowerPlay power analyzer provides better quality estimates based on the specifics of the design after place-and-route is complete. The PowerPlay power analyzer can apply a combination of user-entered, simulation-derived, and estimated signal activities that, combined with detailed circuit models, can yield very accurate power estimates.



For more information about power estimation tools, refer to the *Early Power Estimator User Guide* and the *PowerPlay Power Analysis* chapter in volume 3 of the *Quartus II Handbook*.

Switching Characteristics

This section provides performance characteristics of Cyclone IV core and periphery blocks for commercial grade devices.

These characteristics can be designated as Preliminary or Final.

- Preliminary characteristics are created using simulation results, process data, and other known parameters. The upper-right hand corner of these tables show the designation as “Preliminary”.
- Final numbers are based on actual silicon characterization and testing. The numbers reflect the actual performance of the device under worst-case silicon process, voltage, and junction temperature conditions. There are no designations on finalized tables.

Transceiver Performance Specifications

Table 1-21 lists the Cyclone IV GX transceiver specifications.

Table 1-21. Transceiver Specification for Cyclone IV GX Devices (Part 1 of 4)

Symbol/ Description	Conditions	C6			C7, I7			C8			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
Reference Clock											
Supported I/O Standards	1.2 V PCML, 1.5 V PCML, 3.3 V PCML, Differential LVPECL, LVDS, HCSL										
Input frequency from REFCLK input pins	—	50	—	156.25	50	—	156.25	50	—	156.25	MHz
Spread-spectrum modulating clock frequency	Physical interface for PCI Express (PIPE) mode	30	—	33	30	—	33	30	—	33	kHz
Spread-spectrum downspread	PIPE mode	—	0 to –0.5%	—	—	0 to –0.5%	—	—	0 to –0.5%	—	—
Peak-to-peak differential input voltage	—	0.1	—	1.6	0.1	—	1.6	0.1	—	1.6	V
V _{ICM} (AC coupled)	—	1100 ± 5%			1100 ± 5%			1100 ± 5%			mV
V _{ICM} (DC coupled)	HCSL I/O standard for PCIe reference clock	250	—	550	250	—	550	250	—	550	mV
Transmitter REFCLK Phase Noise ⁽¹⁾	Frequency offset = 1 MHz – 8 MHz	—	—	–123	—	—	–123	—	—	–123	dBc/Hz
Transmitter REFCLK Total Jitter ⁽¹⁾		—	—	42.3	—	—	42.3	—	—	42.3	ps
R _{ref}	—	—	2000 ± 1%	—	—	2000 ± 1%	—	—	2000 ± 1%	—	Ω
Transceiver Clock											
cal_blk_clk clock frequency	—	10	—	125	10	—	125	10	—	125	MHz
fixedclk clock frequency	PCIe Receiver Detect	—	125	—	—	125	—	—	125	—	MHz
reconfig_clk clock frequency	Dynamic reconfiguration clock frequency	2.5/37.5 ⁽²⁾	—	50	2.5/37.5 ⁽²⁾	—	50	2.5/37.5 ⁽²⁾	—	50	MHz
Delta time between reconfig_clk	—	—	—	2	—	—	2	—	—	2	ms
Transceiver block minimum power-down pulse width	—	—	1	—	—	1	—	—	1	—	μs

Table 1–21. Transceiver Specification for Cyclone IV GX Devices (Part 2 of 4)

Symbol/ Description	Conditions	C6			C7, I7			C8			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
Receiver											
Supported I/O Standards	1.4 V PCML, 1.5 V PCML, 2.5 V PCML, LVPECL, LVDS										
Data rate (F324 and smaller package) ⁽¹⁵⁾	—	600	—	2500	600	—	2500	600	—	2500	Mbps
Data rate (F484 and larger package) ⁽¹⁵⁾	—	600	—	3125	600	—	3125	600	—	2500	Mbps
Absolute V _{MAX} for a receiver pin ⁽³⁾	—	—	—	1.6	—	—	1.6	—	—	1.6	V
Operational V _{MAX} for a receiver pin	—	—	—	1.5	—	—	1.5	—	—	1.5	V
Absolute V _{MIN} for a receiver pin	—	–0.4	—	—	–0.4	—	—	–0.4	—	—	V
Peak-to-peak differential input voltage V _{ID} (diff p-p)	V _{ICM} = 0.82 V setting, Data Rate = 600 Mbps to 3.125 Gbps	0.1	—	2.7	0.1	—	2.7	0.1	—	2.7	V
V _{ICM}	V _{ICM} = 0.82 V setting	—	820 ± 10%	—	—	820 ± 10%	—	—	820 ± 10%	—	mV
Differential on-chip termination resistors	100–Ω setting	—	100	—	—	100	—	—	100	—	Ω
	150–Ω setting	—	150	—	—	150	—	—	150	—	Ω
Differential and common mode return loss	PIPE, Serial Rapid I/O SR, SATA, CPRI LV, SDI, XAUI	Compliant									—
Programmable ppm detector ⁽⁴⁾	—	± 62.5, 100, 125, 200, 250, 300									ppm
Clock data recovery (CDR) ppm tolerance (without spread-spectrum clocking enabled)	—	—	—	±300 ⁽⁵⁾ , ±350 ^{(6), (7)}	—	—	±300 ⁽⁵⁾ , ±350 ^{(6), (7)}	—	—	±300 ⁽⁵⁾ , ±350 ^{(6), (7)}	ppm
CDR ppm tolerance (with synchronous spread-spectrum clocking enabled) ⁽⁸⁾	—	—	—	350 to –5350 ^{(7), (9)}	—	—	350 to –5350 ^{(7), (9)}	—	—	350 to –5350 ^{(7), (9)}	ppm
Run length	—	—	80	—	—	80	—	—	80	—	UI
Programmable equalization	No Equalization	—	—	1.5	—	—	1.5	—	—	1.5	dB
	Medium Low	—	—	4.5	—	—	4.5	—	—	4.5	dB
	Medium High	—	—	5.5	—	—	5.5	—	—	5.5	dB
	High	—	—	7	—	—	7	—	—	7	dB

Table 1-21. Transceiver Specification for Cyclone IV GX Devices (Part 3 of 4)

Symbol/ Description	Conditions	C6			C7, I7			C8			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
Signal detect/loss threshold	PIPE mode	65	—	175	65	—	175	65	—	175	mV
t_{LTR} ⁽¹⁰⁾	—	—	—	75	—	—	75	—	—	75	μs
$t_{LTR-LTD_Manual}$ ⁽¹¹⁾	—	15	—	—	15	—	—	15	—	—	μs
t_{LTD} ⁽¹²⁾	—	0	100	4000	0	100	4000	0	100	4000	ns
t_{LTD_Manual} ⁽¹³⁾	—	—	—	4000	—	—	4000	—	—	4000	ns
t_{LTD_Auto} ⁽¹⁴⁾	—	—	—	4000	—	—	4000	—	—	4000	ns
Receiver buffer and CDR offset cancellation time (per channel)	—	—	—	17000	—	—	17000	—	—	17000	recon fig_c lk cycles
Programmable DC gain	DC Gain Setting = 0	—	0	—	—	0	—	—	0	—	dB
	DC Gain Setting = 1	—	3	—	—	3	—	—	3	—	dB
	DC Gain Setting = 2	—	6	—	—	6	—	—	6	—	dB
Transmitter											
Supported I/O Standards	1.5 V PCML										
Data rate (F324 and smaller package)	—	600	—	2500	600	—	2500	600	—	2500	Mbps
Data rate (F484 and larger package)	—	600	—	3125	600	—	3125	600	—	2500	Mbps
V_{OCM}	0.65 V setting	—	650	—	—	650	—	—	650	—	mV
Differential on-chip termination resistors	100-Ω setting	—	100	—	—	100	—	—	100	—	Ω
	150-Ω setting	—	150	—	—	150	—	—	150	—	Ω
Differential and common mode return loss	PIPE, CPRI LV, Serial Rapid I/O SR, SDI, XAUI, SATA	Compliant									—
Rise time	—	50	—	200	50	—	200	50	—	200	ps
Fall time	—	50	—	200	50	—	200	50	—	200	ps
Intra-differential pair skew	—	—	—	15	—	—	15	—	—	15	ps
Intra-transceiver block skew	—	—	—	120	—	—	120	—	—	120	ps

Table 1–23 lists the Cyclone IV GX transceiver block AC specifications.

Table 1–23. Transceiver Block AC Specification for Cyclone IV GX Devices ^{(1), (2)}

Symbol/ Description	Conditions	C6			C7, I7			C8			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
PCIe Transmit Jitter Generation ⁽³⁾											
Total jitter at 2.5 Gbps (Gen1)	Compliance pattern	—	—	0.25	—	—	0.25	—	—	0.25	UI
PCIe Receiver Jitter Tolerance ⁽³⁾											
Total jitter at 2.5 Gbps (Gen1)	Compliance pattern	> 0.6			> 0.6			> 0.6			UI
GIGE Transmit Jitter Generation ⁽⁴⁾											
Deterministic jitter (peak-to-peak)	Pattern = CRPAT	—	—	0.14	—	—	0.14	—	—	0.14	UI
Total jitter (peak-to-peak)	Pattern = CRPAT	—	—	0.279	—	—	0.279	—	—	0.279	UI
GIGE Receiver Jitter Tolerance ⁽⁴⁾											
Deterministic jitter tolerance (peak-to-peak)	Pattern = CJPAT	> 0.4			> 0.4			> 0.4			UI
Combined deterministic and random jitter tolerance (peak-to-peak)	Pattern = CJPAT	> 0.66			> 0.66			> 0.66			UI

Notes to Table 1–23:

- (1) Dedicated `refclk` pins were used to drive the input reference clocks.
- (2) The jitter numbers specified are valid for the stated conditions only.
- (3) The jitter numbers for PIPE are compliant to the PCIe Base Specification 2.0.
- (4) The jitter numbers for GIGE are compliant to the IEEE802.3-2002 Specification.

Core Performance Specifications

The following sections describe the clock tree specifications, PLLs, embedded multiplier, memory block, and configuration specifications for Cyclone IV Devices.

Clock Tree Specifications

Table 1–24 lists the clock tree specifications for Cyclone IV devices.

Table 1–24. Clock Tree Performance for Cyclone IV Devices (Part 1 of 2)

Device	Performance								Unit
	C6	C7	C8	C8L ⁽¹⁾	C9L ⁽¹⁾	I7	I8L ⁽¹⁾	A7	
EP4CE6	500	437.5	402	362	265	437.5	362	402	MHz
EP4CE10	500	437.5	402	362	265	437.5	362	402	MHz
EP4CE15	500	437.5	402	362	265	437.5	362	402	MHz
EP4CE22	500	437.5	402	362	265	437.5	362	402	MHz
EP4CE30	500	437.5	402	362	265	437.5	362	402	MHz
EP4CE40	500	437.5	402	362	265	437.5	362	402	MHz

Table 1–29 lists the active configuration mode specifications for Cyclone IV devices.

Table 1–29. Active Configuration Mode Specifications for Cyclone IV Devices

Programming Mode	DCLK Range	Typical DCLK	Unit
Active Parallel (AP) ⁽¹⁾	20 to 40	33	MHz
Active Serial (AS)	20 to 40	33	MHz

Note to Table 1–29:

(1) AP configuration mode is only supported for Cyclone IV E devices.

Table 1–30 lists the JTAG timing parameters and values for Cyclone IV devices.

Table 1–30. JTAG Timing Parameters for Cyclone IV Devices ⁽¹⁾

Symbol	Parameter	Min	Max	Unit
t _{JCP}	TCK clock period	40	—	ns
t _{JCH}	TCK clock high time	19	—	ns
t _{JCL}	TCK clock low time	19	—	ns
t _{JPSU_TDI}	JTAG port setup time for TDI	1	—	ns
t _{JPSU_TMS}	JTAG port setup time for TMS	3	—	ns
t _{JPH}	JTAG port hold time	10	—	ns
t _{JPCO}	JTAG port clock to output ^{(2), (3)}	—	15	ns
t _{JPZX}	JTAG port high impedance to valid output ^{(2), (3)}	—	15	ns
t _{JPXZ}	JTAG port valid output to high impedance ^{(2), (3)}	—	15	ns
t _{JSSU}	Capture register setup time	5	—	ns
t _{JSH}	Capture register hold time	10	—	ns
t _{JSCO}	Update register clock to output	—	25	ns
t _{JSZX}	Update register high impedance to valid output	—	25	ns
t _{JSXZ}	Update register valid output to high impedance	—	25	ns

Notes to Table 1–30:

(1) For more information about JTAG waveforms, refer to “JTAG Waveform” in “Glossary” on page 1–37.

(2) The specification is shown for 3.3-, 3.0-, and 2.5-V LVTTTL/LVCMOS operation of JTAG pins. For 1.8-V LVTTTL/LVCMOS and 1.5-V LVCMOS, the output time specification is 16 ns.

(3) For EP4CGX22, EP4CGX30 (F324 and smaller package), EP4CGX110, and EP4CGX150 devices, the output time specification for 3.3-, 3.0-, and 2.5-V LVTTTL/LVCMOS operation of JTAG pins is 16 ns. For 1.8-V LVTTTL/LVCMOS and 1.5-V LVCMOS, the output time specification is 18 ns.

Periphery Performance

This section describes periphery performance, including high-speed I/O and external memory interface.

I/O performance supports several system interfaces, such as the high-speed I/O interface, external memory interface, and the PCI/PCI-X bus interface. I/Os using the SSTL-18 Class I termination standard can achieve up to the stated DDR2 SDRAM interfacing speeds. I/Os using general-purpose I/O standards such as 3.3-, 3.0-, 2.5-, 1.8-, or 1.5-LVTTTL/LVCMOS are capable of a typical 200 MHz interfacing frequency with a 10 pF load.

Table 1–32. Emulated RSDS_E_1R Transmitter Timing Specifications for Cyclone IV Devices ^{(1), (3)} (Part 2 of 2)

Symbol	Modes	C6			C7, I7			C8, A7			C8L, I8L			C9L			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
t _{LOCK} ⁽²⁾	—	—	—	1	—	—	1	—	—	1	—	—	1	—	—	1	ms

Notes to Table 1–32:

- (1) Emulated RSDS_E_1R transmitter is supported at the output pin of all I/O Banks of Cyclone IV E devices and I/O Banks 3, 4, 5, 6, 7, 8, and 9 of Cyclone IV GX devices.
- (2) t_{LOCK} is the time required for the PLL to lock from the end-of-device configuration.
- (3) Cyclone IV E 1.0 V core voltage devices only support C8L, C9L, and I8L speed grades. Cyclone IV E 1.2 V core voltage devices only support C6, C7, C8, I7, and A7 speed grades. Cyclone IV GX devices only support C6, C7, C8, and I7 speed grades.

Table 1–33. Mini-LVDS Transmitter Timing Specifications for Cyclone IV Devices ^{(1), (2), (4)}

Symbol	Modes	C6			C7, I7			C8, A7			C8L, I8L			C9L			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
f _{HSCLK} (input clock frequency)	×10	5	—	200	5	—	155.5	5	—	155.5	5	—	155.5	5	—	132.5	MHz
	×8	5	—	200	5	—	155.5	5	—	155.5	5	—	155.5	5	—	132.5	MHz
	×7	5	—	200	5	—	155.5	5	—	155.5	5	—	155.5	5	—	132.5	MHz
	×4	5	—	200	5	—	155.5	5	—	155.5	5	—	155.5	5	—	132.5	MHz
	×2	5	—	200	5	—	155.5	5	—	155.5	5	—	155.5	5	—	132.5	MHz
	×1	5	—	400	5	—	311	5	—	311	5	—	311	5	—	265	MHz
Device operation in Mbps	×10	100	—	400	100	—	311	100	—	311	100	—	311	100	—	265	Mbps
	×8	80	—	400	80	—	311	80	—	311	80	—	311	80	—	265	Mbps
	×7	70	—	400	70	—	311	70	—	311	70	—	311	70	—	265	Mbps
	×4	40	—	400	40	—	311	40	—	311	40	—	311	40	—	265	Mbps
	×2	20	—	400	20	—	311	20	—	311	20	—	311	20	—	265	Mbps
	×1	10	—	400	10	—	311	10	—	311	10	—	311	10	—	265	Mbps
t _{DUTY}	—	45	—	55	45	—	55	45	—	55	45	—	55	45	—	55	%
TCCS	—	—	—	200	—	—	200	—	—	200	—	—	200	—	—	200	ps
Output jitter (peak to peak)	—	—	—	500	—	—	500	—	—	550	—	—	600	—	—	700	ps
t _{RISE}	20 – 80%, C _{LOAD} = 5 pF	—	500	—	—	500	—	—	500	—	—	500	—	—	500	—	ps
t _{FALL}	20 – 80%, C _{LOAD} = 5 pF	—	500	—	—	500	—	—	500	—	—	500	—	—	500	—	ps
t _{LOCK} ⁽³⁾	—	—	—	1	—	—	1	—	—	1	—	—	1	—	—	1	ms

Notes to Table 1–33:

- (1) Applicable for true and emulated mini-LVDS transmitter.
- (2) Cyclone IV E—true mini-LVDS transmitter is only supported at the output pin of Row I/O Banks 1, 2, 5, and 6. Emulated mini-LVDS transmitter is supported at the output pin of all I/O banks.
Cyclone IV GX—true mini-LVDS transmitter is only supported at the output pin of Row I/O Banks 5 and 6. Emulated mini-LVDS transmitter is supported at the output pin of I/O Banks 3, 4, 5, 6, 7, 8, and 9.
- (3) t_{LOCK} is the time required for the PLL to lock from the end-of-device configuration.
- (4) Cyclone IV E 1.0 V core voltage devices only support C8L, C9L, and I8L speed grades. Cyclone IV E 1.2 V core voltage devices only support C6, C7, C8, I7, and A7 speed grades. Cyclone IV GX devices only support C6, C7, C8, and I7 speed grades.

Table 1–34. True LVDS Transmitter Timing Specifications for Cyclone IV Devices ⁽¹⁾, ⁽³⁾

Symbol	Modes	C6		C7, I7		C8, A7		C8L, I8L		C9L		Unit
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
f _{HCLK} (input clock frequency)	×10	5	420	5	370	5	320	5	320	5	250	MHz
	×8	5	420	5	370	5	320	5	320	5	250	MHz
	×7	5	420	5	370	5	320	5	320	5	250	MHz
	×4	5	420	5	370	5	320	5	320	5	250	MHz
	×2	5	420	5	370	5	320	5	320	5	250	MHz
	×1	5	420	5	402.5	5	402.5	5	362	5	265	MHz
HSIODR	×10	100	840	100	740	100	640	100	640	100	500	Mbps
	×8	80	840	80	740	80	640	80	640	80	500	Mbps
	×7	70	840	70	740	70	640	70	640	70	500	Mbps
	×4	40	840	40	740	40	640	40	640	40	500	Mbps
	×2	20	840	20	740	20	640	20	640	20	500	Mbps
	×1	10	420	10	402.5	10	402.5	10	362	10	265	Mbps
t _{DUTY}	—	45	55	45	55	45	55	45	55	45	55	%
TCCS	—	—	200	—	200	—	200	—	200	—	200	ps
Output jitter (peak to peak)	—	—	500	—	500	—	550	—	600	—	700	ps
t _{LOCK} ⁽²⁾	—	—	1	—	1	—	1	—	1	—	1	ms

Notes to Table 1–34:

- (1) Cyclone IV E—true LVDS transmitter is only supported at the output pin of Row I/O Banks 1, 2, 5, and 6.
Cyclone IV GX—true LVDS transmitter is only supported at the output pin of Row I/O Banks 5 and 6.
- (2) t_{LOCK} is the time required for the PLL to lock from the end-of-device configuration.
- (3) Cyclone IV E 1.0 V core voltage devices only support C8L, C9L, and I8L speed grades. Cyclone IV E 1.2 V core voltage devices only support C6, C7, C8, I7, and A7 speed grades. Cyclone IV GX devices only support C6, C7, C8, and I7 speed grades.

Table 1–35. Emulated LVDS Transmitter Timing Specifications for Cyclone IV Devices ⁽¹⁾, ⁽³⁾ (Part 1 of 2)

Symbol	Modes	C6		C7, I7		C8, A7		C8L, I8L		C9L		Unit
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
f _{HCLK} (input clock frequency)	×10	5	320	5	320	5	275	5	275	5	250	MHz
	×8	5	320	5	320	5	275	5	275	5	250	MHz
	×7	5	320	5	320	5	275	5	275	5	250	MHz
	×4	5	320	5	320	5	275	5	275	5	250	MHz
	×2	5	320	5	320	5	275	5	275	5	250	MHz
	×1	5	402.5	5	402.5	5	402.5	5	362	5	265	MHz
HSIODR	×10	100	640	100	640	100	550	100	550	100	500	Mbps
	×8	80	640	80	640	80	550	80	550	80	500	Mbps
	×7	70	640	70	640	70	550	70	550	70	500	Mbps
	×4	40	640	40	640	40	550	40	550	40	500	Mbps
	×2	20	640	20	640	20	550	20	550	20	500	Mbps
	×1	10	402.5	10	402.5	10	402.5	10	362	10	265	Mbps

Table 1–42 and Table 1–43 list the IOE programmable delay for Cyclone IV E 1.2 V core voltage devices.

Table 1–42. IOE Programmable Delay on Column Pins for Cyclone IV E 1.2 V Core Voltage Devices ^{(1), (2)}

Parameter	Paths Affected	Number of Setting	Min Offset	Max Offset								Unit
				Fast Corner			Slow Corner					
				C6	I7	A7	C6	C7	C8	I7	A7	
Input delay from pin to internal cells	Pad to I/O dataout to core	7	0	1.314	1.211	1.211	2.177	2.340	2.433	2.388	2.508	ns
Input delay from pin to input register	Pad to I/O input register	8	0	1.307	1.203	1.203	2.19	2.387	2.540	2.430	2.545	ns
Delay from output register to output pin	I/O output register to pad	2	0	0.437	0.402	0.402	0.747	0.820	0.880	0.834	0.873	ns
Input delay from dual-purpose clock pin to fan-out destinations	Pad to global clock network	12	0	0.693	0.665	0.665	1.200	1.379	1.532	1.393	1.441	ns

Notes to Table 1–42:

- (1) The incremental values for the settings are generally linear. For the exact values for each setting, use the latest version of the Quartus II software.
- (2) The minimum and maximum offset timing numbers are in reference to setting **0** as available in the Quartus II software.

Table 1–43. IOE Programmable Delay on Row Pins for Cyclone IV E 1.2 V Core Voltage Devices ^{(1), (2)}

Parameter	Paths Affected	Number of Setting	Min Offset	Max Offset								Unit
				Fast Corner			Slow Corner					
				C6	I7	A7	C6	C7	C8	I7	A7	
Input delay from pin to internal cells	Pad to I/O dataout to core	7	0	1.314	1.209	1.209	2.201	2.386	2.510	2.429	2.548	ns
Input delay from pin to input register	Pad to I/O input register	8	0	1.312	1.207	1.207	2.202	2.402	2.558	2.447	2.557	ns
Delay from output register to output pin	I/O output register to pad	2	0	0.458	0.419	0.419	0.783	0.861	0.924	0.875	0.915	ns
Input delay from dual-purpose clock pin to fan-out destinations	Pad to global clock network	12	0	0.686	0.657	0.657	1.185	1.360	1.506	1.376	1.422	ns

Notes to Table 1–43:

- (1) The incremental values for the settings are generally linear. For the exact values for each setting, use the latest version of the Quartus II software.
- (2) The minimum and maximum offset timing numbers are in reference to setting **0** as available in the Quartus II software.

Table 1–44 and Table 1–45 list the IOE programmable delay for Cyclone IV GX devices.

Table 1–44. IOE Programmable Delay on Column Pins for Cyclone IV GX Devices ^{(1), (2)}

Parameter	Paths Affected	Number of Settings	Min Offset	Max Offset						Unit
				Fast Corner		Slow Corner				
				C6	I7	C6	C7	C8	I7	
Input delay from pin to internal cells	Pad to I/O dataout to core	7	0	1.313	1.209	2.184	2.336	2.451	2.387	ns
Input delay from pin to input register	Pad to I/O input register	8	0	1.312	1.208	2.200	2.399	2.554	2.446	ns
Delay from output register to output pin	I/O output register to pad	2	0	0.438	0.404	0.751	0.825	0.886	0.839	ns
Input delay from dual-purpose clock pin to fan-out destinations	Pad to global clock network	12	0	0.713	0.682	1.228	1.41	1.566	1.424	ns

Notes to Table 1–44:

- (1) The incremental values for the settings are generally linear. For exact values of each setting, use the latest version of the Quartus II software.
- (2) The minimum and maximum offset timing numbers are in reference to setting **0** as available in the Quartus II software.

Table 1–45. IOE Programmable Delay on Row Pins for Cyclone IV GX Devices ^{(1), (2)}

Parameter	Paths Affected	Number of Settings	Min Offset	Max Offset						Unit
				Fast Corner		Slow Corner				
				C6	I7	C6	C7	C8	I7	
Input delay from pin to internal cells	Pad to I/O dataout to core	7	0	1.314	1.210	2.209	2.398	2.526	2.443	ns
Input delay from pin to input register	Pad to I/O input register	8	0	1.313	1.208	2.205	2.406	2.563	2.450	ns
Delay from output register to output pin	I/O output register to pad	2	0	0.461	0.421	0.789	0.869	0.933	0.884	ns
Input delay from dual-purpose clock pin to fan-out destinations	Pad to global clock network	12	0	0.712	0.682	1.225	1.407	1.562	1.421	ns

Notes to Table 1–45:

- (1) The incremental values for the settings are generally linear. For exact values of each setting, use the latest version of Quartus II software.
- (2) The minimum and maximum offset timing numbers are in reference to setting **0** as available in the Quartus II software

I/O Timing

Use the following methods to determine I/O timing:

- the Excel-based I/O Timing
- the Quartus II timing analyzer

The Excel-based I/O timing provides pin timing performance for each device density and speed grade. The data is typically used prior to designing the FPGA to get a timing budget estimation as part of the link timing analysis. The Quartus II timing analyzer provides a more accurate and precise I/O timing data based on the specifics of the design after place-and-route is complete.



The Excel-based I/O Timing spreadsheet is downloadable from Cyclone IV Devices Literature website.

Glossary

Table 1–46 lists the glossary for this chapter.

Table 1–46. Glossary (Part 1 of 5)

Letter	Term	Definitions
A	—	—
B	—	—
C	—	—
D	—	—
E	—	—
F	f_{HSCLK}	High-speed I/O block: High-speed receiver/transmitter input and output clock frequency.
G	GCLK	Input pin directly to Global Clock network.
	GCLK PLL	Input pin to Global Clock network through the PLL.
H	HSIODR	High-speed I/O block: Maximum/minimum LVDS data transfer rate ($\text{HSIODR} = 1/\text{TUI}$).
I	Input Waveforms for the SSTL Differential I/O Standard	

Table 1-46. Glossary (Part 4 of 5)

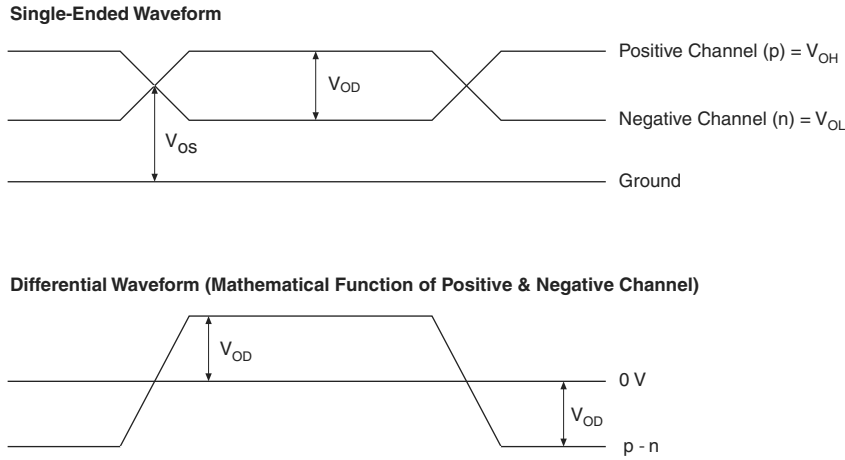
Letter	Term	Definitions
T	t_C	High-speed receiver and transmitter input and output clock period.
	Channel-to-channel-skew (TCCS)	High-speed I/O block: The timing difference between the fastest and slowest output edges, including t_{CO} variation and clock skew. The clock is included in the TCCS measurement.
	t_{cin}	Delay from the clock pad to the I/O input register.
	t_{CO}	Delay from the clock pad to the I/O output.
	t_{cout}	Delay from the clock pad to the I/O output register.
	t_{DUTY}	High-speed I/O block: Duty cycle on high-speed transmitter output clock.
	t_{FALL}	Signal high-to-low transition time (80–20%).
	t_H	Input register hold time.
	Timing Unit Interval (TUI)	High-speed I/O block: The timing budget allowed for skew, propagation delays, and data sampling window. (TUI = $1/(\text{Receiver Input Clock Frequency Multiplication Factor}) = t_C/w$).
	$t_{INJITTER}$	Period jitter on the PLL clock input.
	$t_{OUTJITTER_DEDCLK}$	Period jitter on the dedicated clock output driven by a PLL.
	$t_{OUTJITTER_IO}$	Period jitter on the general purpose I/O driven by a PLL.
	t_{pllcin}	Delay from the PLL inclk pad to the I/O input register.
	$t_{pllcout}$	Delay from the PLL inclk pad to the I/O output register.
	Transmitter Output Waveform	<p>Transmitter output waveforms for the LVDS, mini-LVDS, PPDS and RSDS Differential I/O Standards:</p> 
	t_{RISE}	Signal low-to-high transition time (20–80%).
	t_{SU}	Input register setup time.
U	—	—

Table 1–46. Glossary (Part 5 of 5)

Letter	Term	Definitions
V	$V_{CM(DC)}$	DC common mode input voltage.
	$V_{DIF(AC)}$	AC differential input voltage: The minimum AC input differential voltage required for switching.
	$V_{DIF(DC)}$	DC differential input voltage: The minimum DC input differential voltage required for switching.
	V_{ICM}	Input common mode voltage: The common mode of the differential signal at the receiver.
	V_{ID}	Input differential voltage swing: The difference in voltage between the positive and complementary conductors of a differential transmission at the receiver.
	V_{IH}	Voltage input high: The minimum positive voltage applied to the input that is accepted by the device as a logic high.
	$V_{IH(AC)}$	High-level AC input voltage.
	$V_{IH(DC)}$	High-level DC input voltage.
	V_{IL}	Voltage input low: The maximum positive voltage applied to the input that is accepted by the device as a logic low.
	$V_{IL(AC)}$	Low-level AC input voltage.
	$V_{IL(DC)}$	Low-level DC input voltage.
	V_{IN}	DC input voltage.
	V_{OCM}	Output common mode voltage: The common mode of the differential signal at the transmitter.
	V_{OD}	Output differential voltage swing: The difference in voltage between the positive and complementary conductors of a differential transmission at the transmitter. $V_{OD} = V_{OH} - V_{OL}$.
	V_{OH}	Voltage output high: The maximum positive voltage from an output that the device considers is accepted as the minimum positive high level.
	V_{OL}	Voltage output low: The maximum positive voltage from an output that the device considers is accepted as the maximum positive low level.
	V_{OS}	Output offset voltage: $V_{OS} = (V_{OH} + V_{OL}) / 2$.
	$V_{OX(AC)}$	AC differential output cross point voltage: the voltage at which the differential output signals must cross.
	V_{REF}	Reference voltage for the SSTL and HSTL I/O standards.
	$V_{REF(AC)}$	AC input reference voltage for the SSTL and HSTL I/O standards. $V_{REF(AC)} = V_{REF(DC)} + \text{noise}$. The peak-to-peak AC noise on V_{REF} must not exceed 2% of $V_{REF(DC)}$.
	$V_{REF(DC)}$	DC input reference voltage for the SSTL and HSTL I/O standards.
	$V_{SWING(AC)}$	AC differential input voltage: AC input differential voltage required for switching. For the SSTL differential I/O standard, refer to Input Waveforms.
	$V_{SWING(DC)}$	DC differential input voltage: DC input differential voltage required for switching. For the SSTL differential I/O standard, refer to Input Waveforms.
	V_{TT}	Termination voltage for the SSTL and HSTL I/O standards.
	$V_X(AC)$	AC differential input cross point voltage: The voltage at which the differential input signals must cross.
W	—	—
X	—	—
Y	—	—
Z	—	—

Document Revision History

Table 1-47 lists the revision history for this chapter.

Table 1-47. Document Revision History

Date	Version	Changes
March 2016	2.0	Updated note (5) in Table 1-21 to remove support for the N148 package.
October 2014	1.9	Updated maximum value for V_{CCD_PLL} in Table 1-1. Removed extended temperature note in Table 1-3.
December 2013	1.8	Updated Table 1-21 by adding Note (15).
May 2013	1.7	Updated Table 1-15 by adding Note (4).
October 2012	1.6	<ul style="list-style-type: none"> ■ Updated the maximum value for V_I, V_{CCD_PLL}, V_{CCIO}, V_{CC_CLKIN}, V_{CCH_GXB}, and V_{CCA_GXB} in Table 1-1. ■ Updated Table 1-11 and Table 1-22. ■ Updated Table 1-21 to include peak-to-peak differential input voltage for the Cyclone IV GX transceiver input reference clock. ■ Updated Table 1-29 to include the typical $DCLK$ value. ■ Updated the minimum f_{HCLK} value in Table 1-31, Table 1-32, Table 1-33, Table 1-34, and Table 1-35.
November 2011	1.5	<ul style="list-style-type: none"> ■ Updated “Maximum Allowed Overshoot or Undershoot Voltage”, “Operating Conditions”, and “PLL Specifications” sections. ■ Updated Table 1-2, Table 1-3, Table 1-4, Table 1-5, Table 1-8, Table 1-9, Table 1-15, Table 1-18, Table 1-19, and Table 1-21. ■ Updated Figure 1-1.
December 2010	1.4	<ul style="list-style-type: none"> ■ Updated for the Quartus II software version 10.1 release. ■ Updated Table 1-21 and Table 1-25. ■ Minor text edits.
July 2010	1.3	<p>Updated for the Quartus II software version 10.0 release:</p> <ul style="list-style-type: none"> ■ Updated Table 1-3, Table 1-4, Table 1-21, Table 1-25, Table 1-28, Table 1-30, Table 1-40, Table 1-41, Table 1-42, Table 1-43, Table 1-44, and Table 1-45. ■ Updated Figure 1-2 and Figure 1-3. ■ Removed SW Requirement and TCCS for Cyclone IV Devices tables. ■ Minor text edits.
March 2010	1.2	<p>Updated to include automotive devices:</p> <ul style="list-style-type: none"> ■ Updated the “Operating Conditions” and “PLL Specifications” sections. ■ Updated Table 1-1, Table 1-8, Table 1-9, Table 1-21, Table 1-26, Table 1-27, Table 1-31, Table 1-32, Table 1-33, Table 1-34, Table 1-35, Table 1-36, Table 1-37, Table 1-38, Table 1-40, Table 1-42, and Table 1-43. ■ Added Table 1-5 to include ESD for Cyclone IV devices GPIOs and HSSI I/Os. ■ Added Table 1-44 and Table 1-45 to include IOE programmable delay for Cyclone IV E 1.2 V core voltage devices. ■ Minor text edits.